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(12) **United States Design Patent** (10) **Patent No.:** **US D984,909 S**  
**Singh et al.** (45) **Date of Patent:** **\*\* May 2, 2023**

(54) **THERMOMETER PROBE**  
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(52) **U.S. Cl.**  
USPC ..... **D10/60**  
(58) **Field of Classification Search**  
USPC .... D10/50, 53, 56, 57, 58, 60, 104.1, 104.2,  
D10/121; D24/135, 186, 187  
CPC ..... G01K 1/08; G01K 1/14; G01K 13/20;  
G01K 2207/02  
See application file for complete search history.

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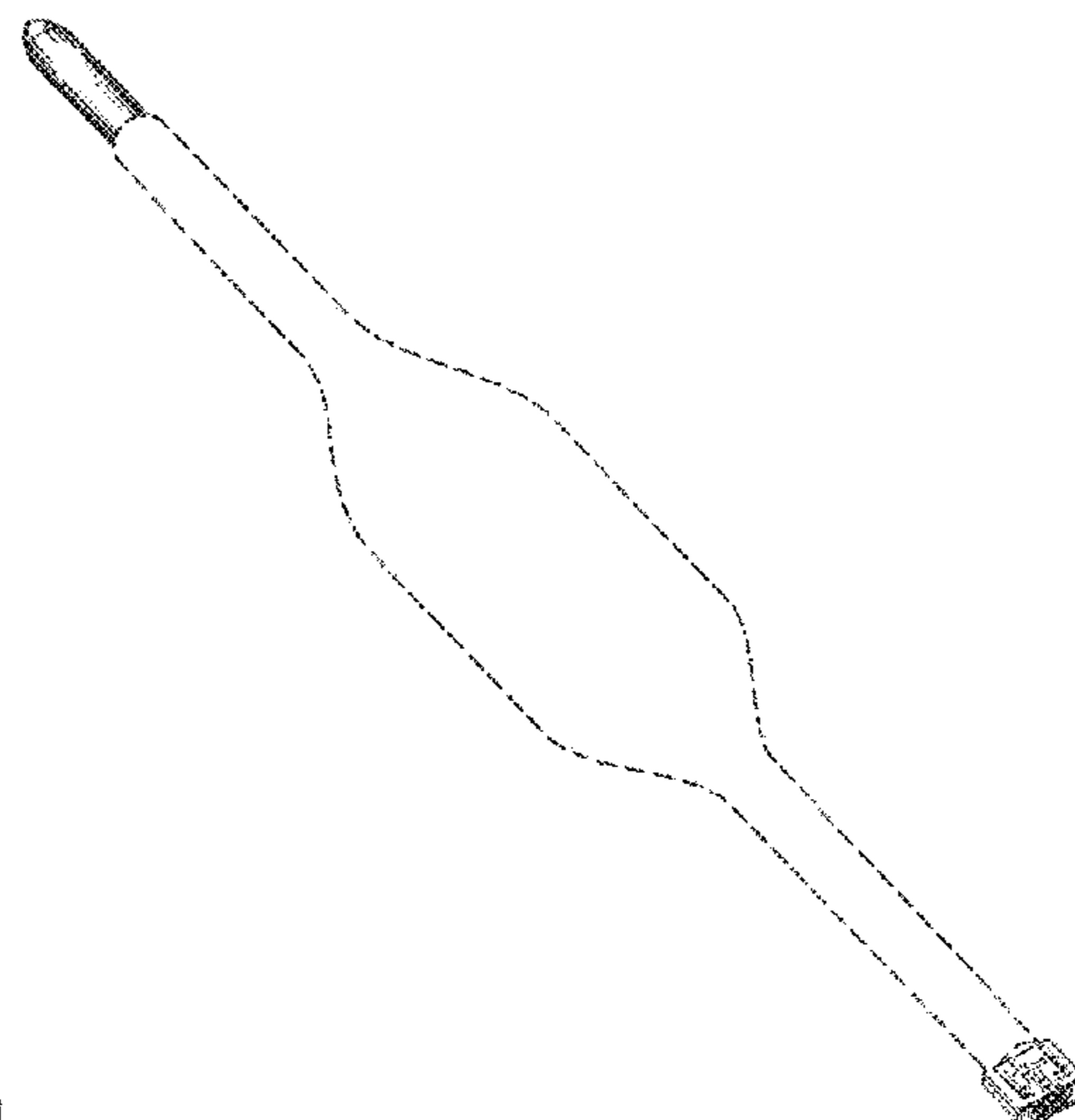
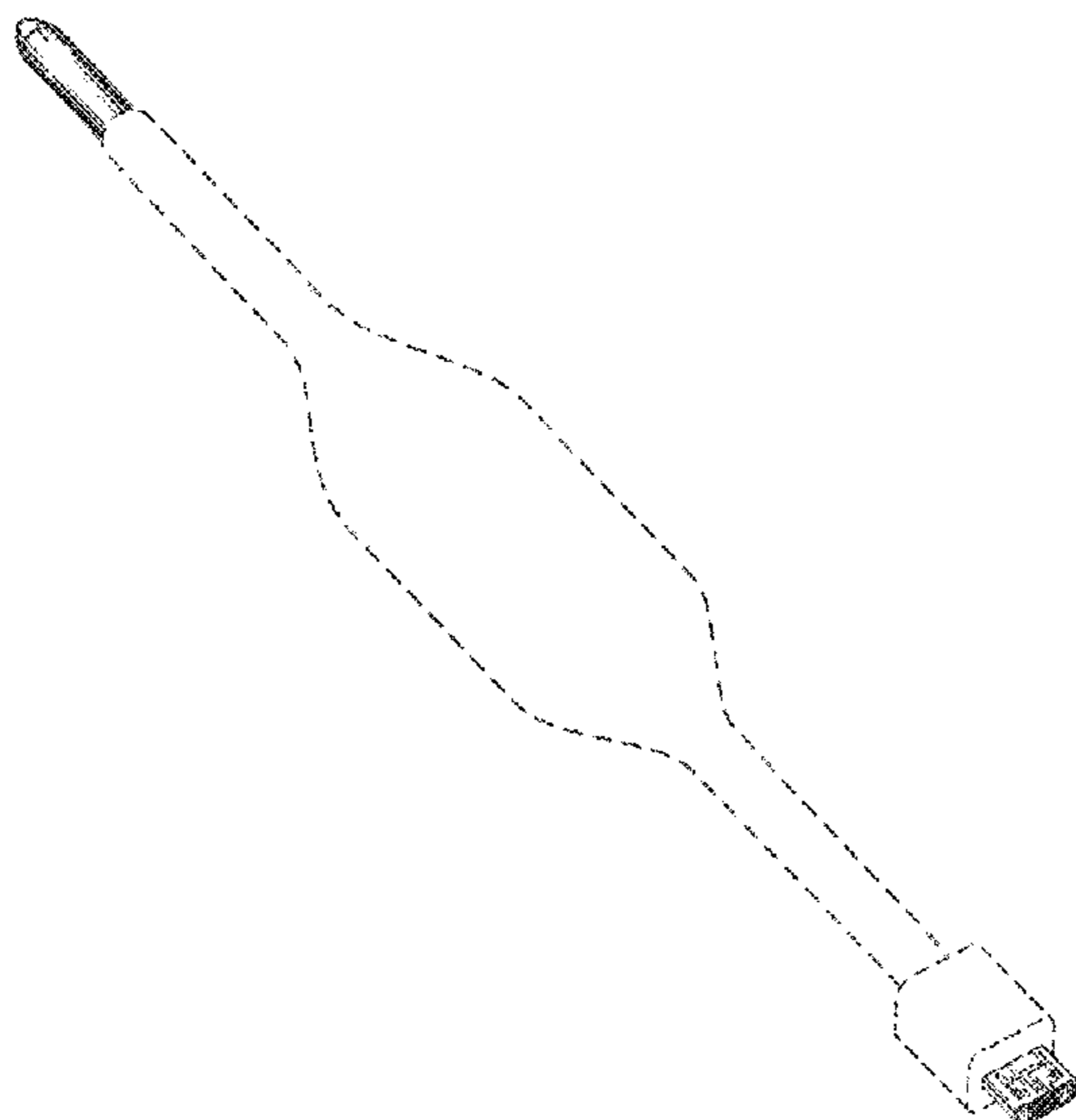
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*Assistant Examiner* — Lillian Windham  
(74) *Attorney, Agent, or Firm* — Ulmer & Berne LLP

(57) **CLAIM**  
The ornamental design for a thermometer probe, as shown and described.

**DESCRIPTION**  
FIG. 1 is a top perspective view of a thermometer probe showing a first image in a first embodiment of the claimed design;  
FIG. 2 is a bottom perspective view thereof;  
FIG. 3 is a front view thereof;  
FIG. 4 is a back view thereof;  
FIG. 5 is a side view thereof;  
FIG. 6 is a bottom view thereof;  
FIG. 7 is a top view thereof;  
FIG. 8 is a top perspective view of a thermometer probe showing a first image in a second embodiment of the claimed design;  
FIG. 9 is a bottom perspective view thereof;  
FIG. 10 is a front view thereof;  
FIG. 11 is a back view thereof;  
FIG. 12 is a side view thereof;  
FIG. 13 is a bottom view thereof;  
FIG. 14 is a top view thereof;  
FIG. 15 is a top perspective view of a thermometer probe showing a first image in a third embodiment of the claimed design;  
FIG. 16 is a bottom perspective view thereof;  
FIG. 17 is a front view thereof;  
FIG. 18 is a back view thereof;  
FIG. 19 is a side view thereof;  
FIG. 20 is a bottom view thereof; and,  
FIG. 21 is a top view thereof.  
The broken lines are included for the purpose of illustrating portions of the thermometer probe that form no part of the claimed design.

**1 Claim, 18 Drawing Sheets**



(56)

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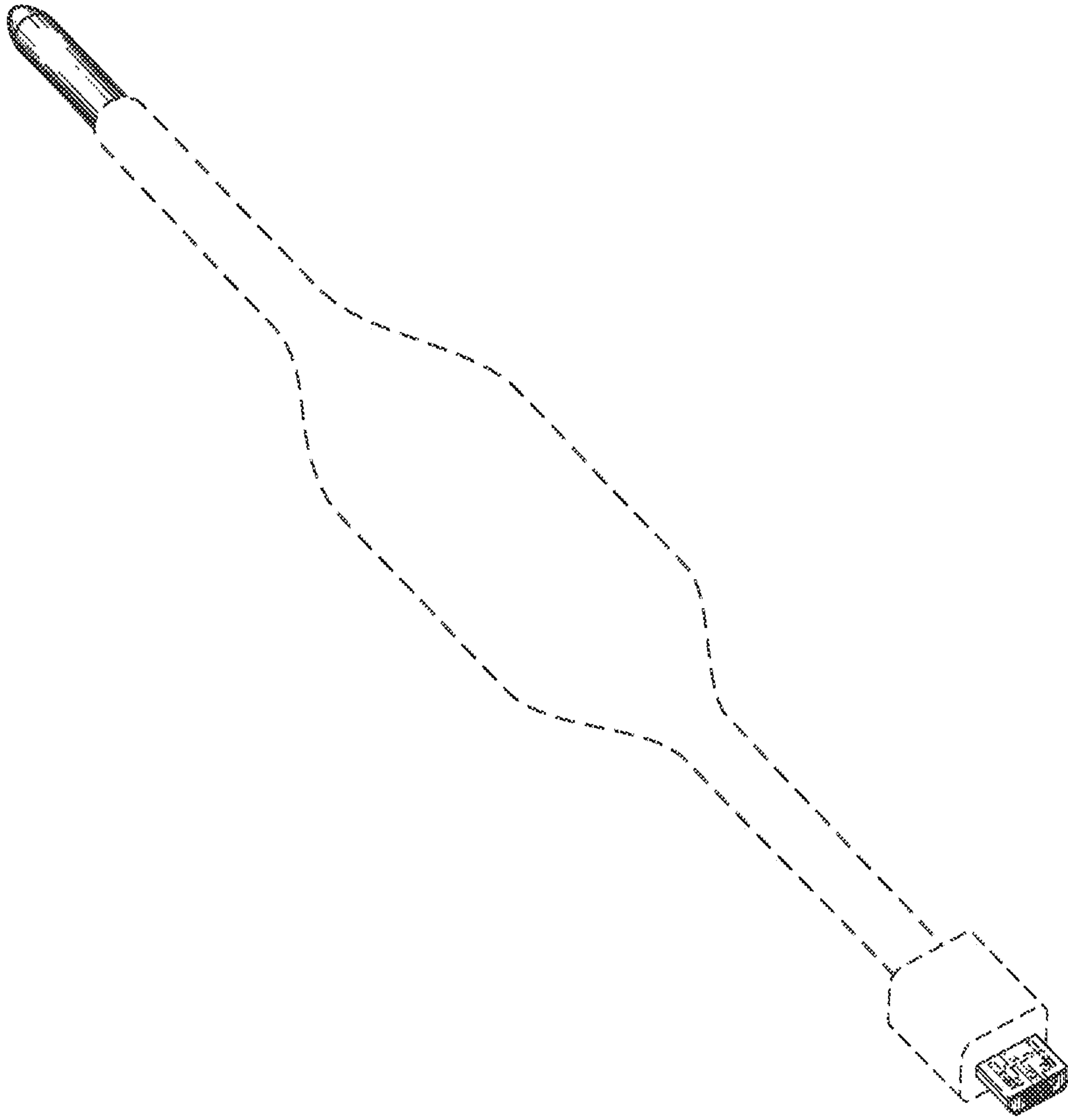


Fig. 1

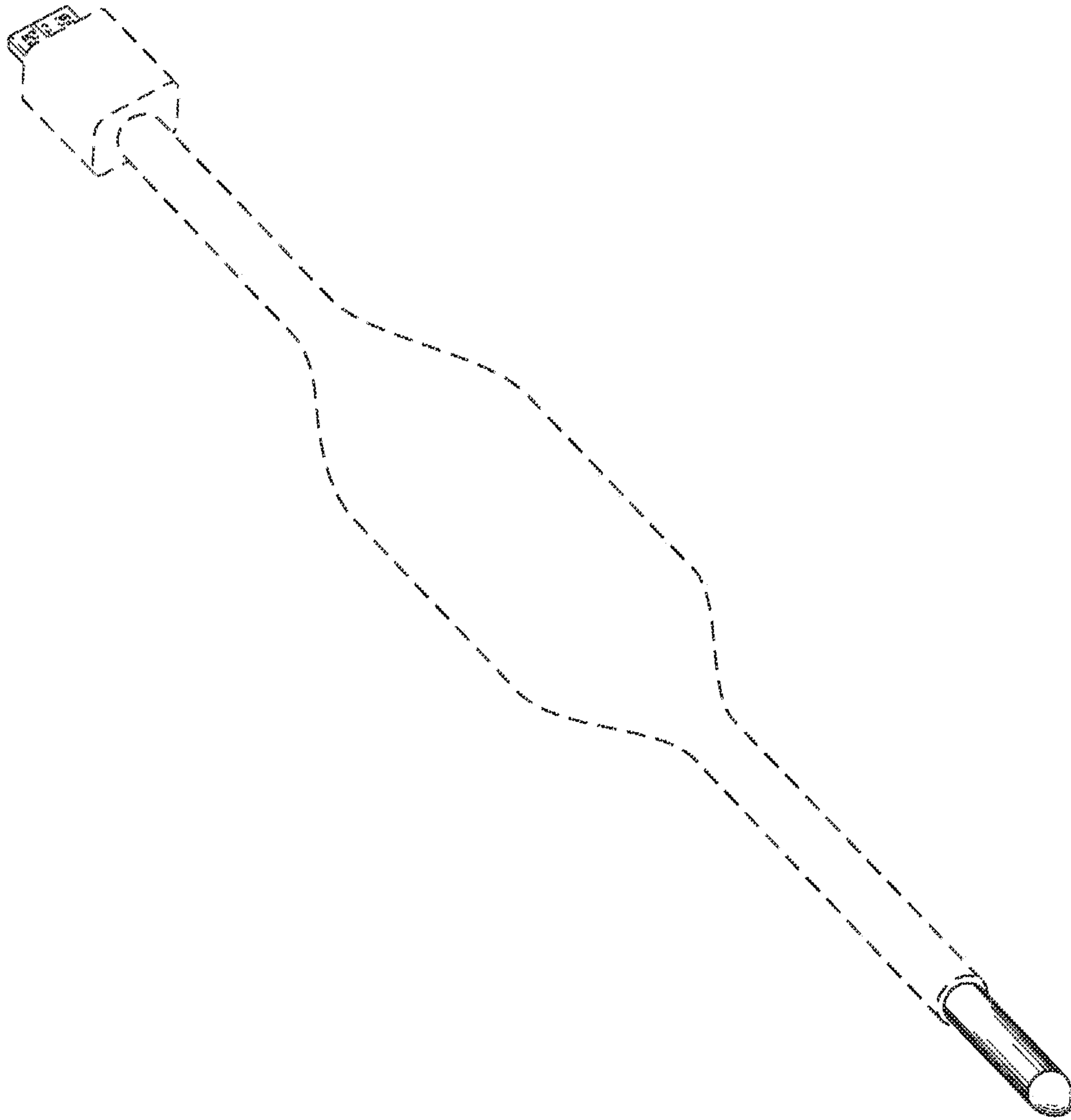


Fig. 2

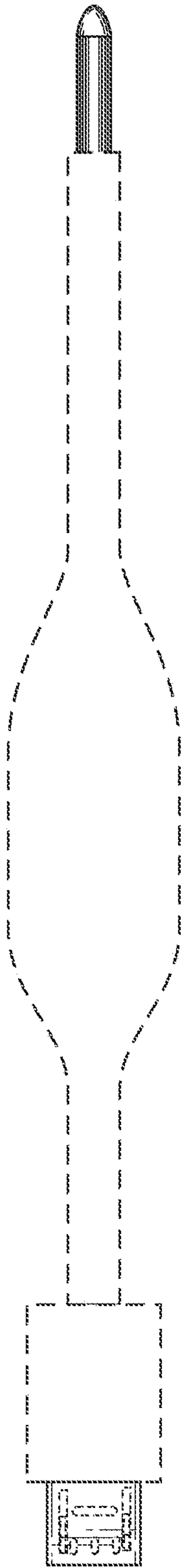


Fig. 3

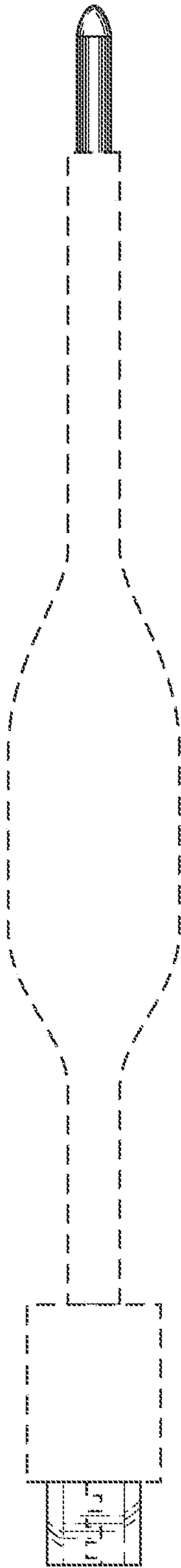


Fig. 4

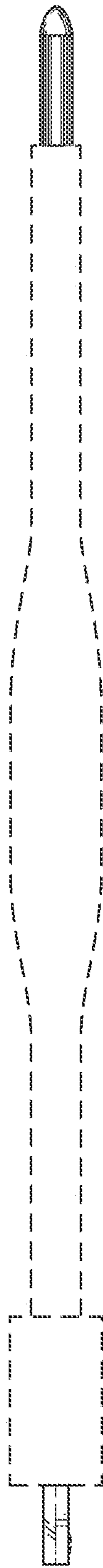


Fig. 5

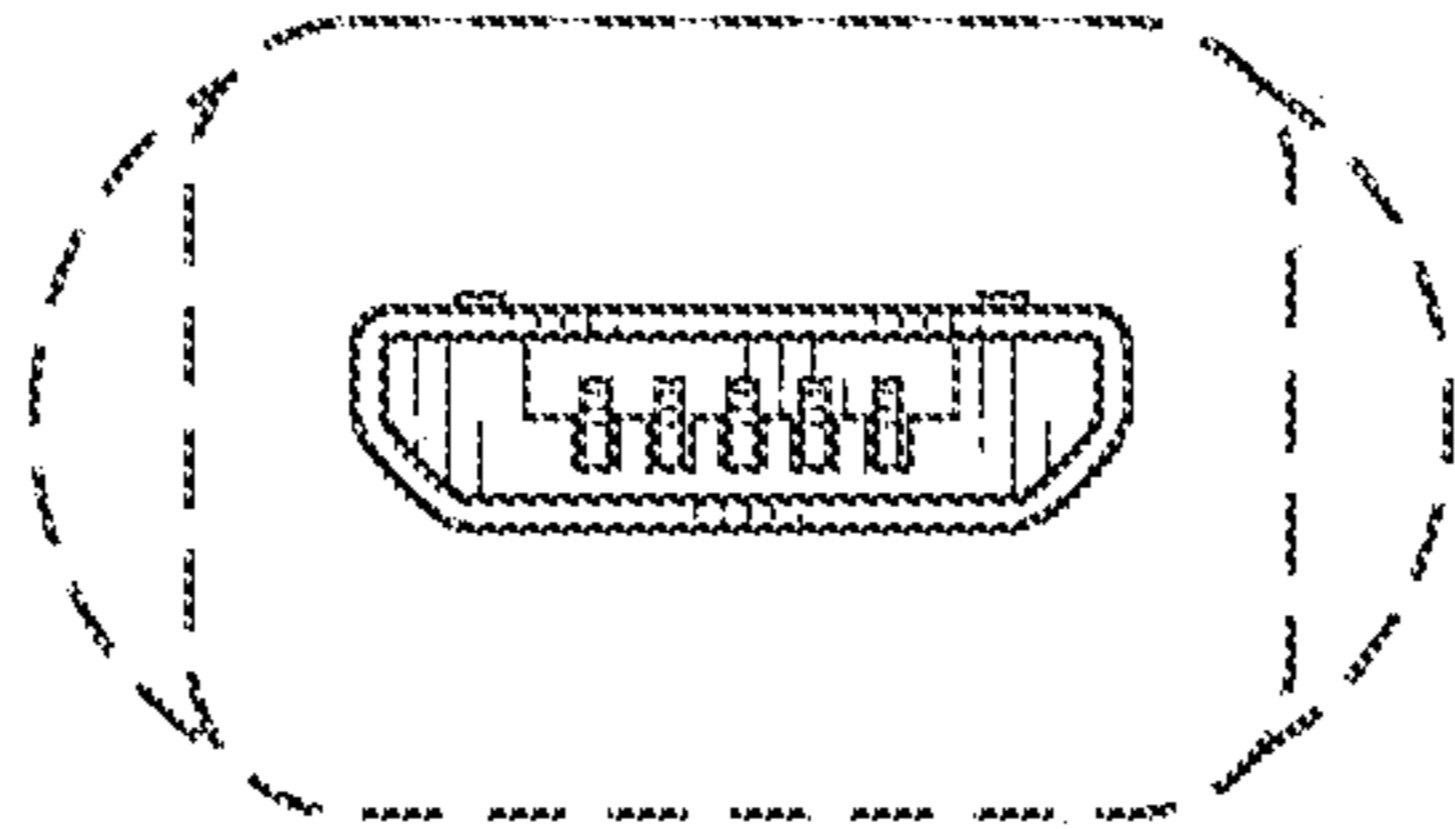


Fig. 6

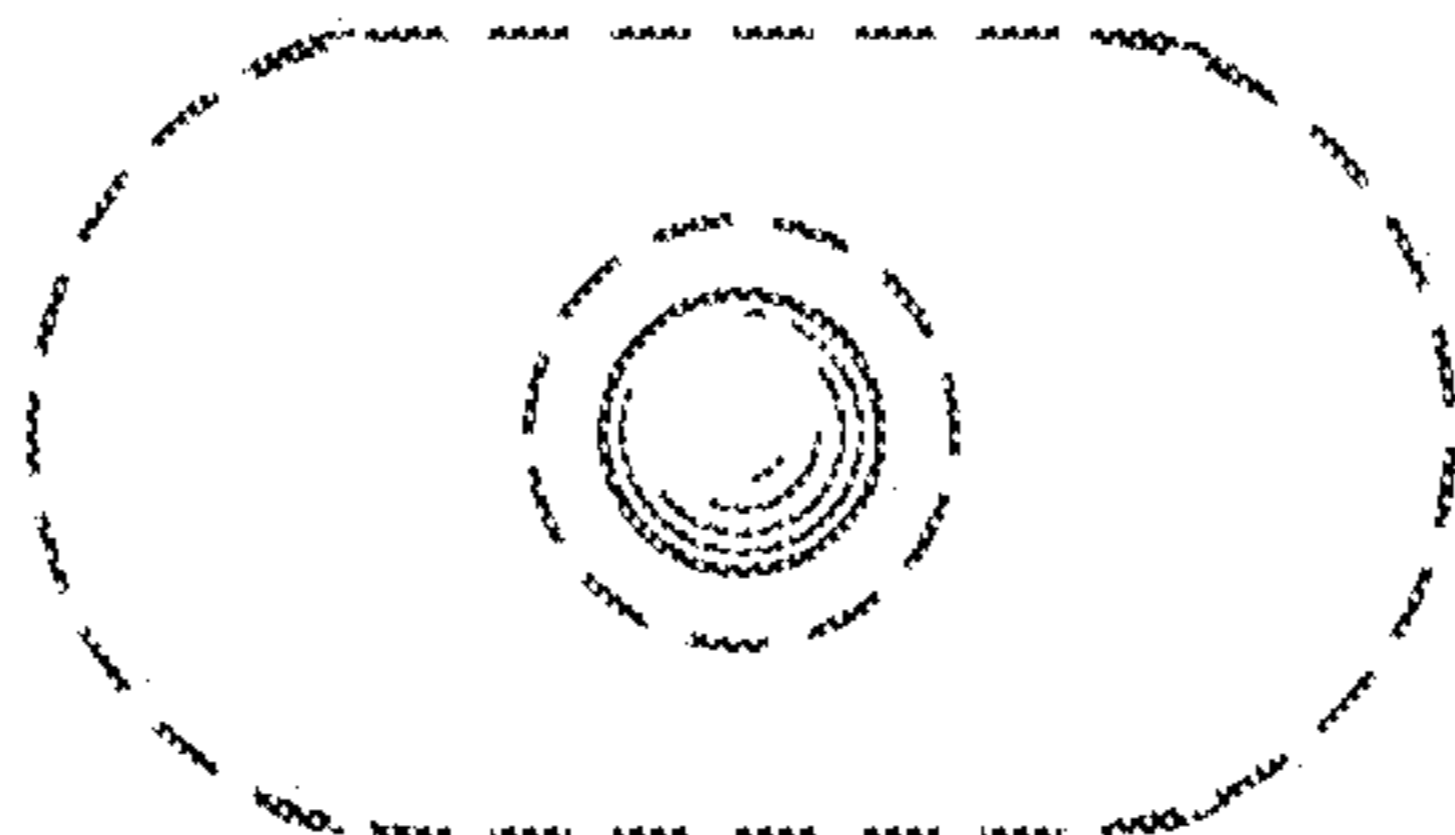


Fig. 7



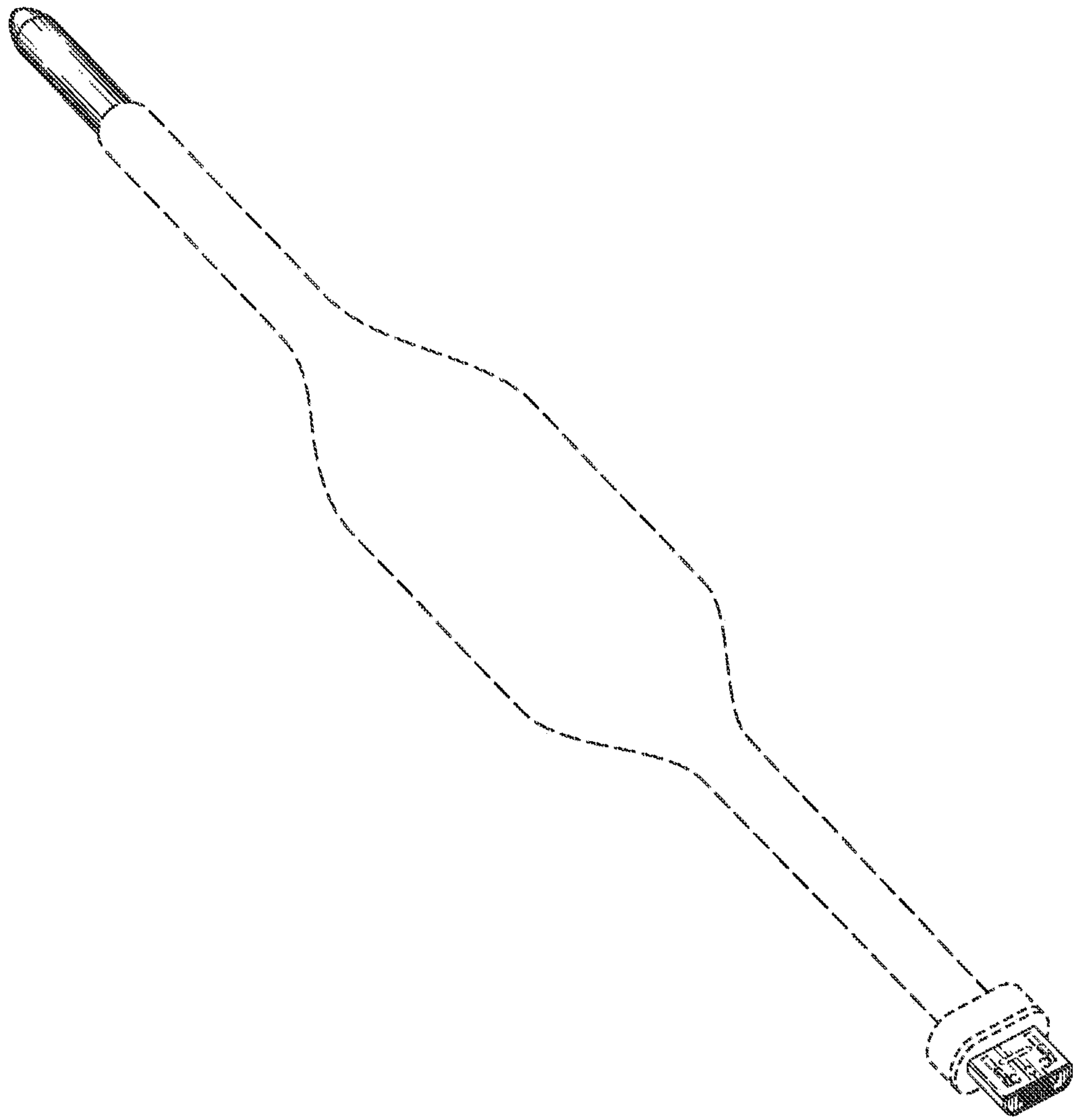


Fig. 8

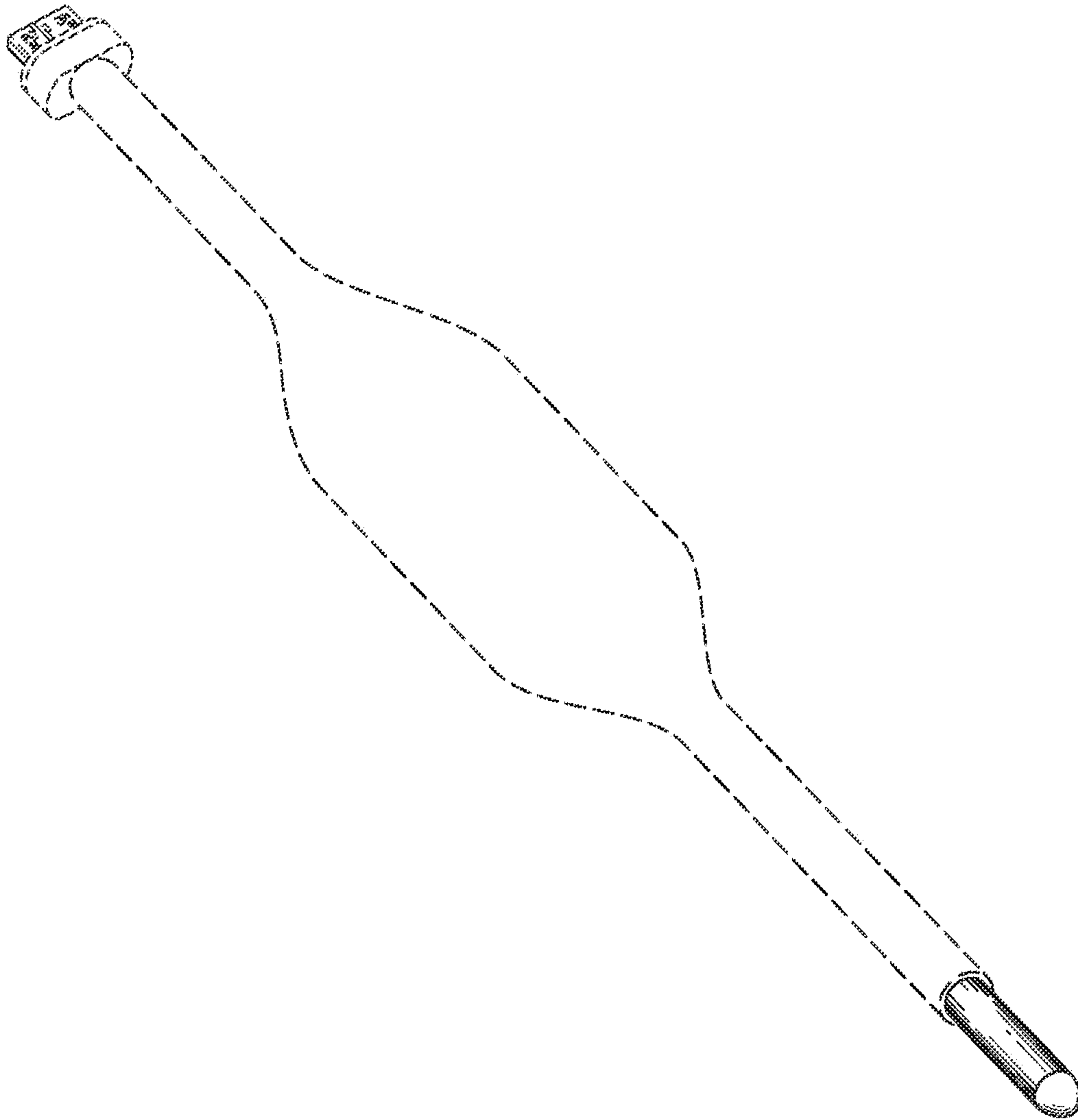


Fig. 9

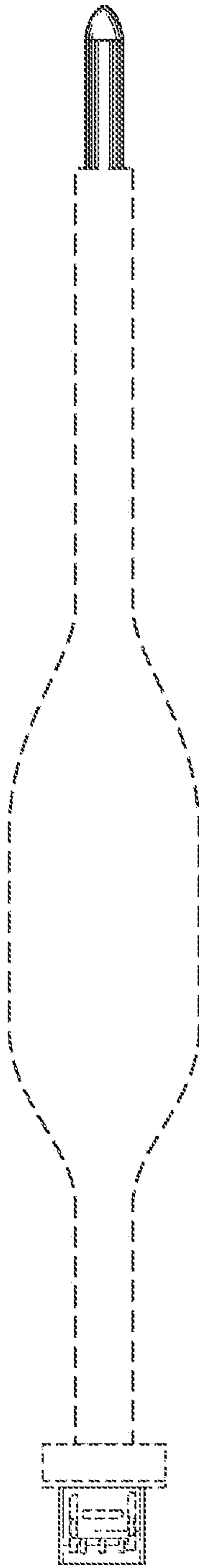


Fig. 10

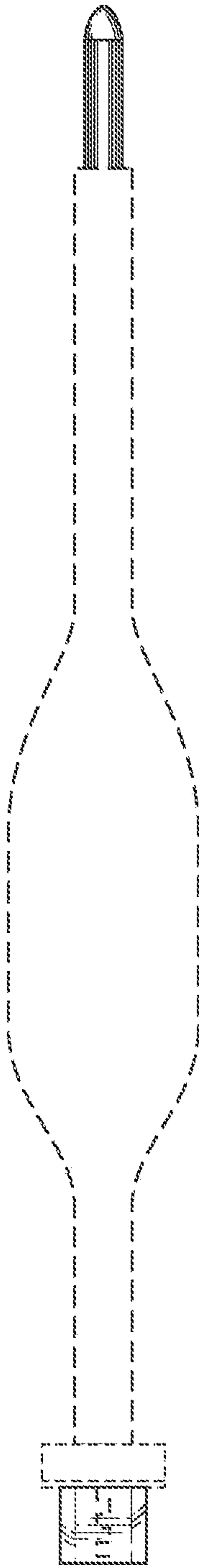


Fig. 11

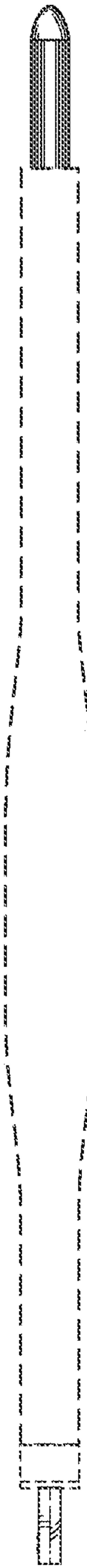


Fig. 12

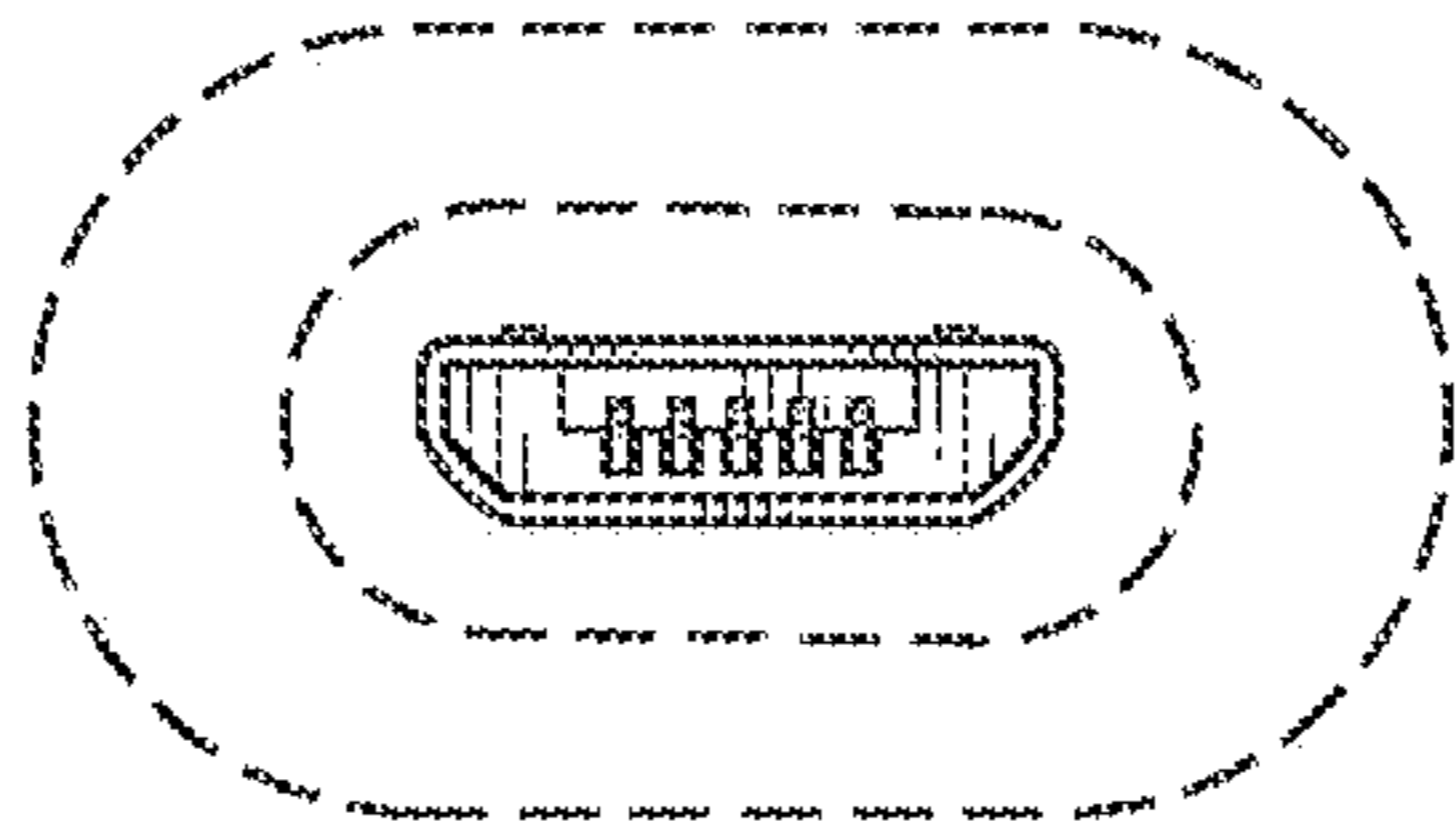


Fig. 13

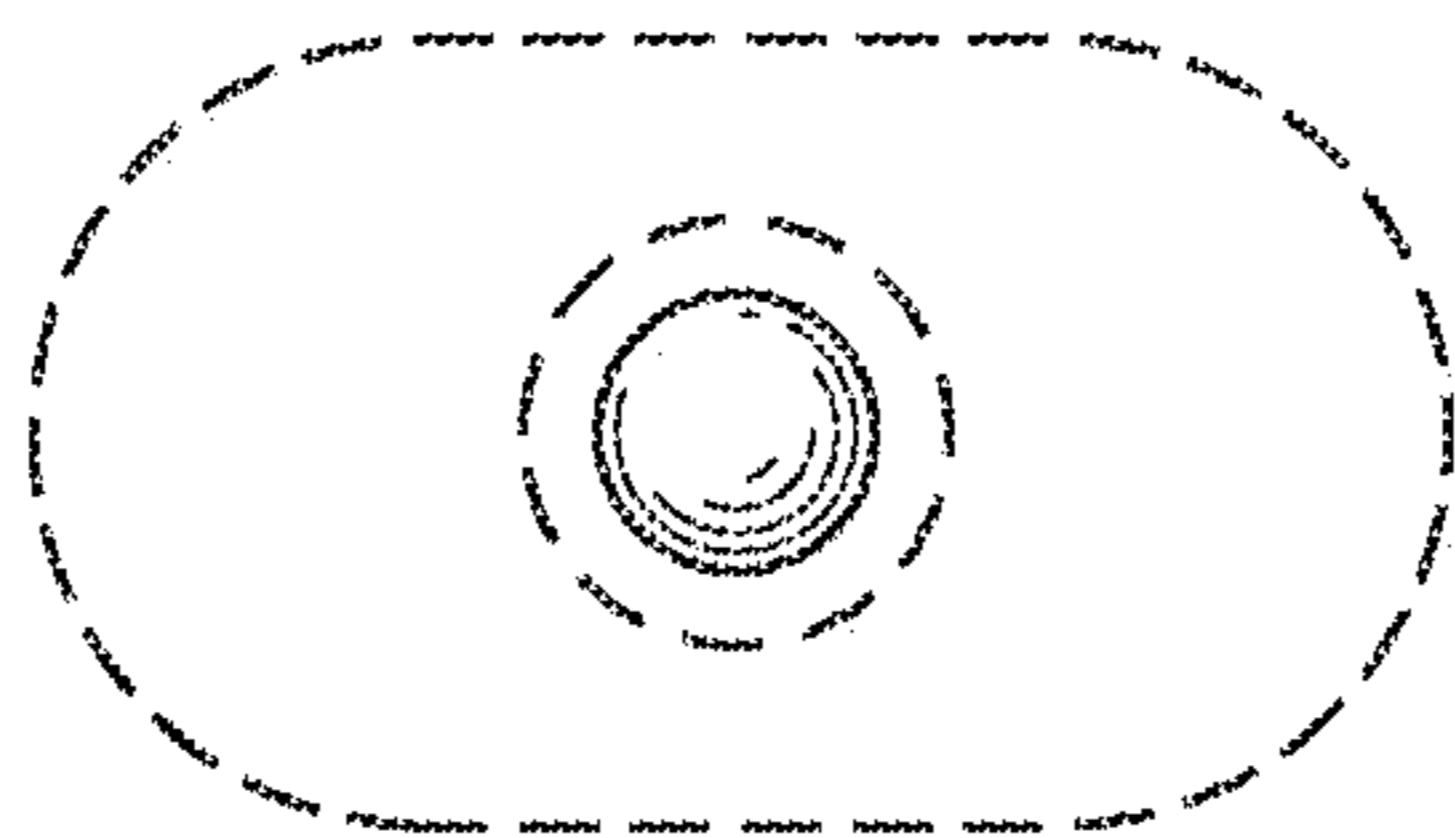


Fig. 14

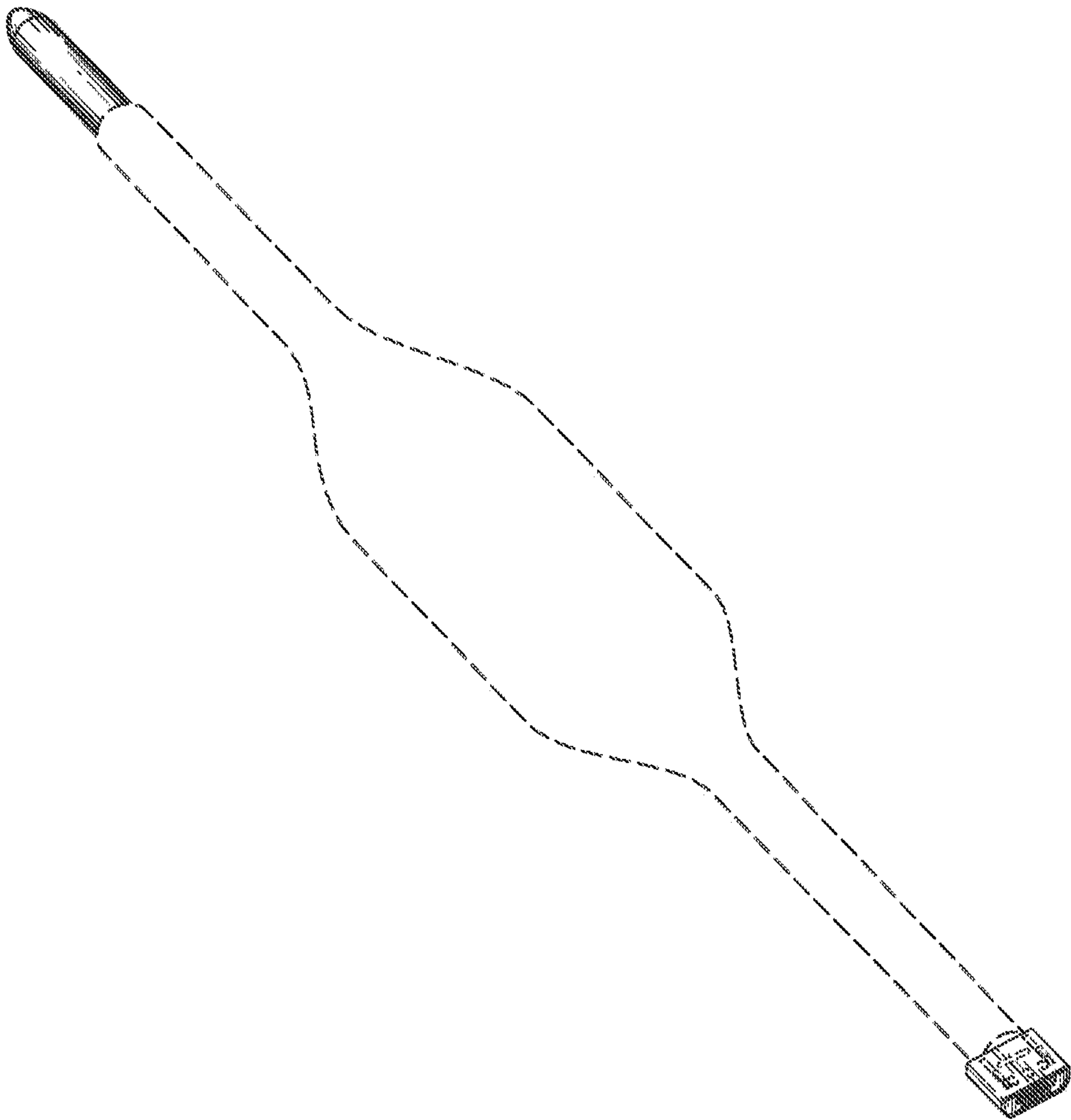


Fig. 15

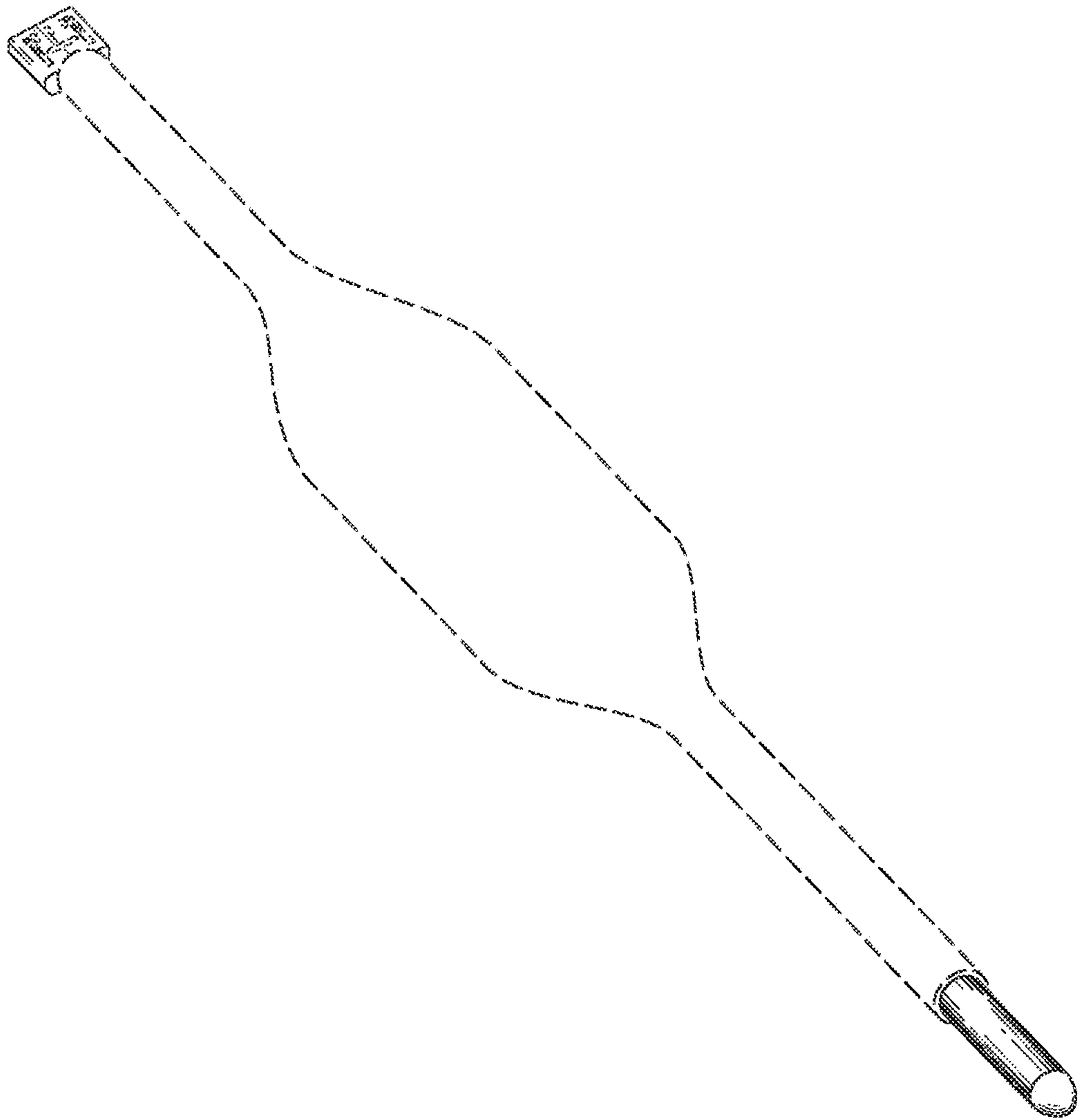


Fig. 16



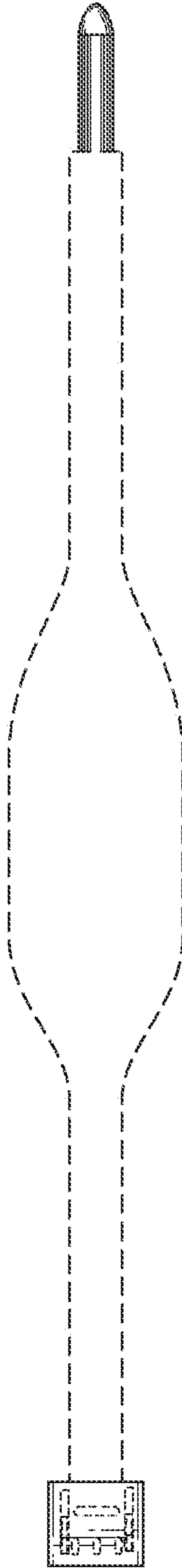


Fig. 17

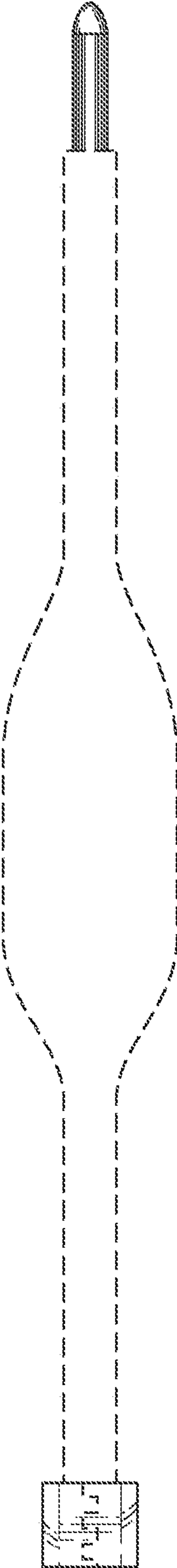


Fig. 18

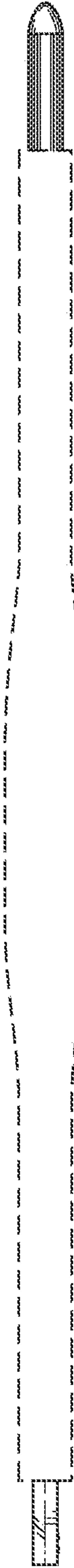


Fig. 19

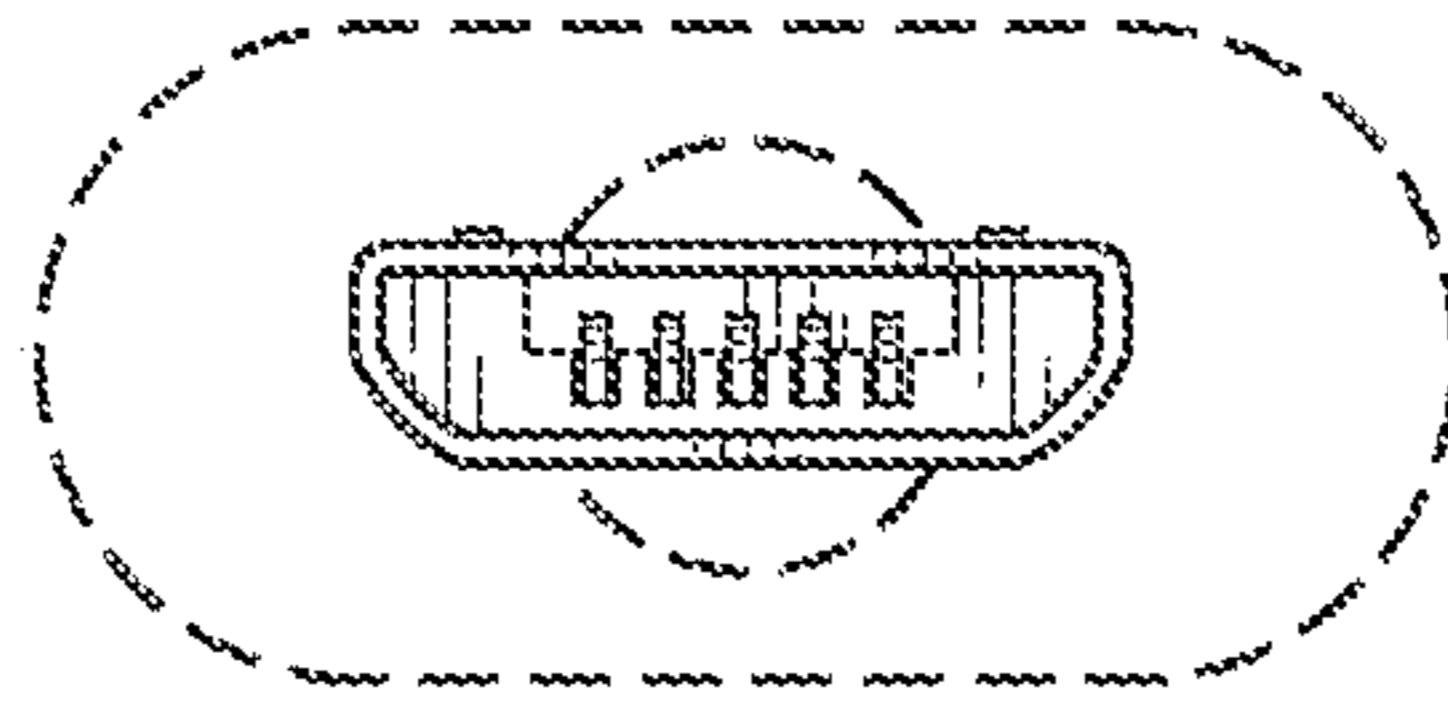


Fig. 20

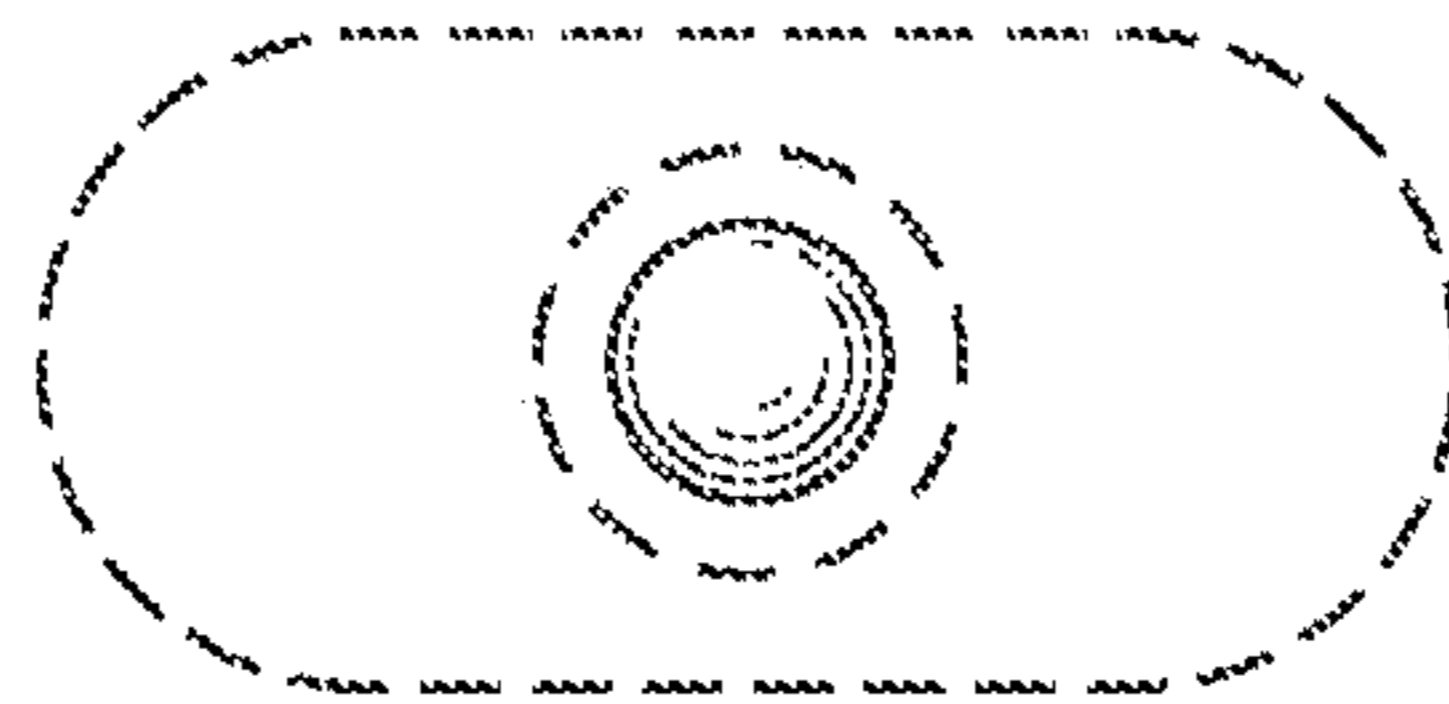


Fig. 21